

Fabrication of Improved Quadrant-type X-band High-Gradient Accelerating Structure

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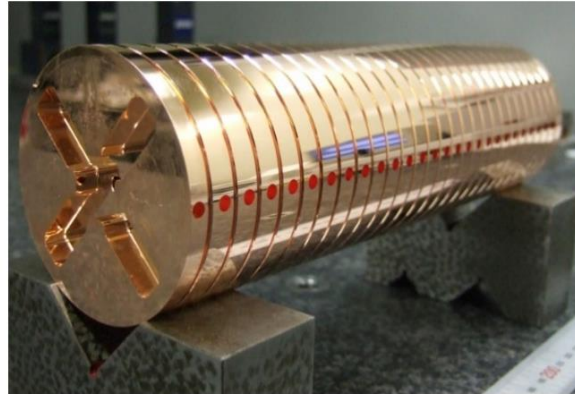
October 30, 2019

Disk-type v.s. Quadrant(or Half)-type

Disk-type



A damped disk



Disks stacked and bonded

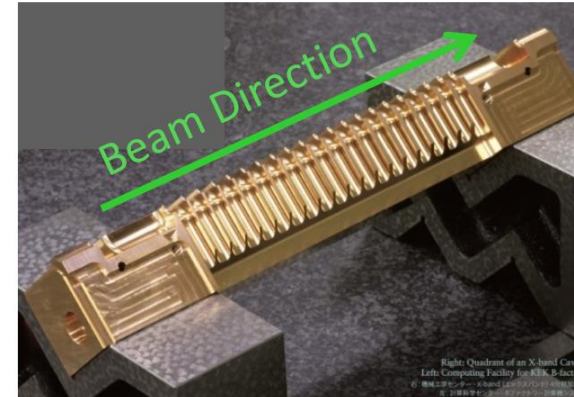
■ Advantages

- ✓ Machining by turning for main parts
- ✓ Very smooth surface ($R_a \approx 30 \text{ nm}$)
- ✓ Shallow machining damage (depth $< 1 \text{ }\mu\text{m}$)

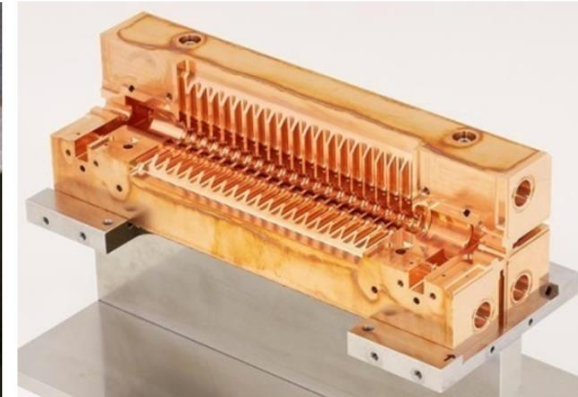
■ Disadvantages

- ✓ Ultraprecision machining of dozen of disks
→ Delicate stack and bonding
- ✓ Great care needed to be taken
- ✓ **Surface currents flow across disk-to-disk junctions.**

Quadrant-type



A Quadrant



Three Quadrants

■ Advantages

- ✓ **Surface currents do not flow across any bonding junction.**
- ✓ Simple machining by five-axes milling machines
- ✓ Simple assembly process with FOUR parts only
→ Possibility of significant cost reduction

■ Disadvantages

- ✓ Not very smooth surface ($R_a \approx 0.3 \text{ }\mu\text{m}$)
- ✓ Deep machining damage ($\sim 10 \text{ }\mu\text{m}$?)
- ✓ **Possible virtual leak from quadrant-to-quadrant junctions**
- ✓ **Field enhancements at the edges of quadrants**

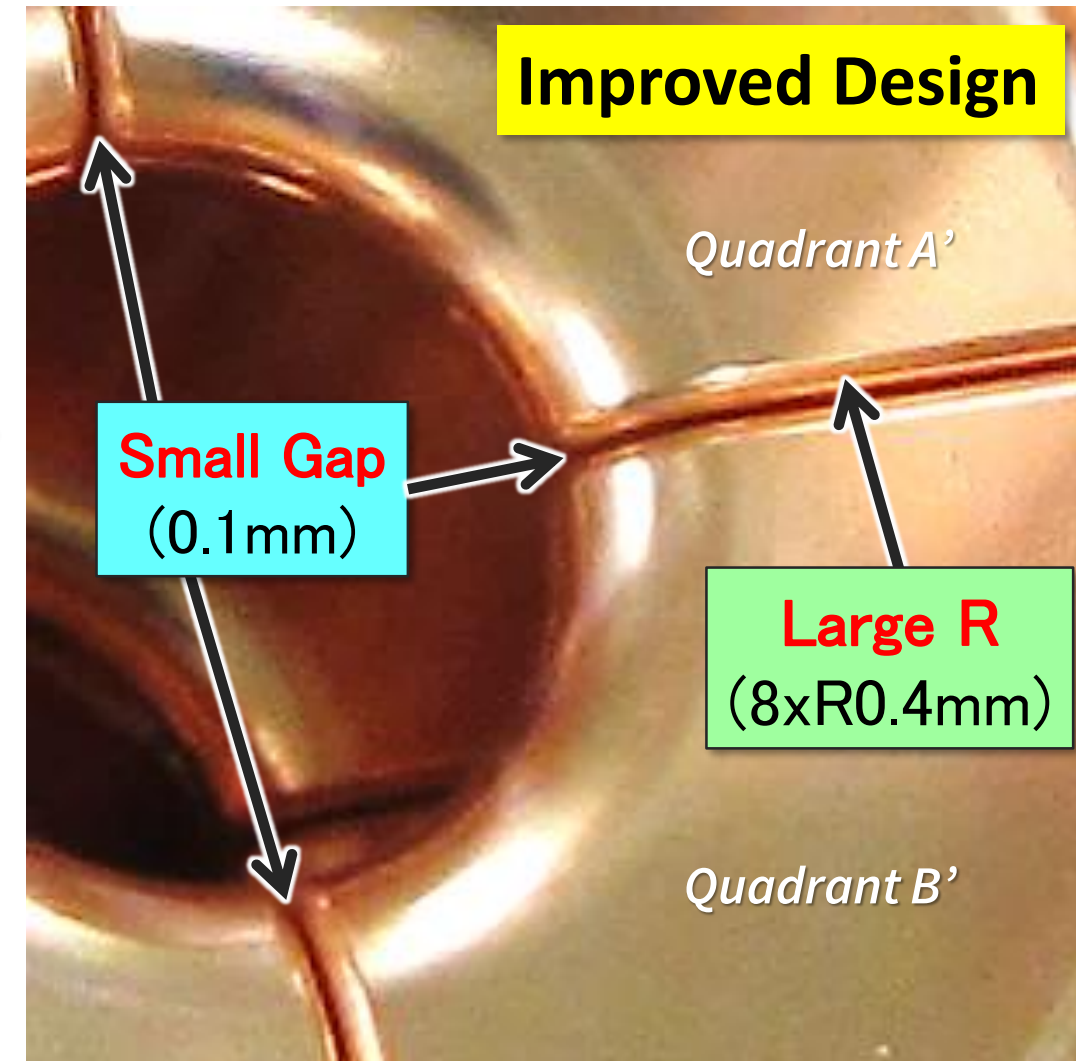
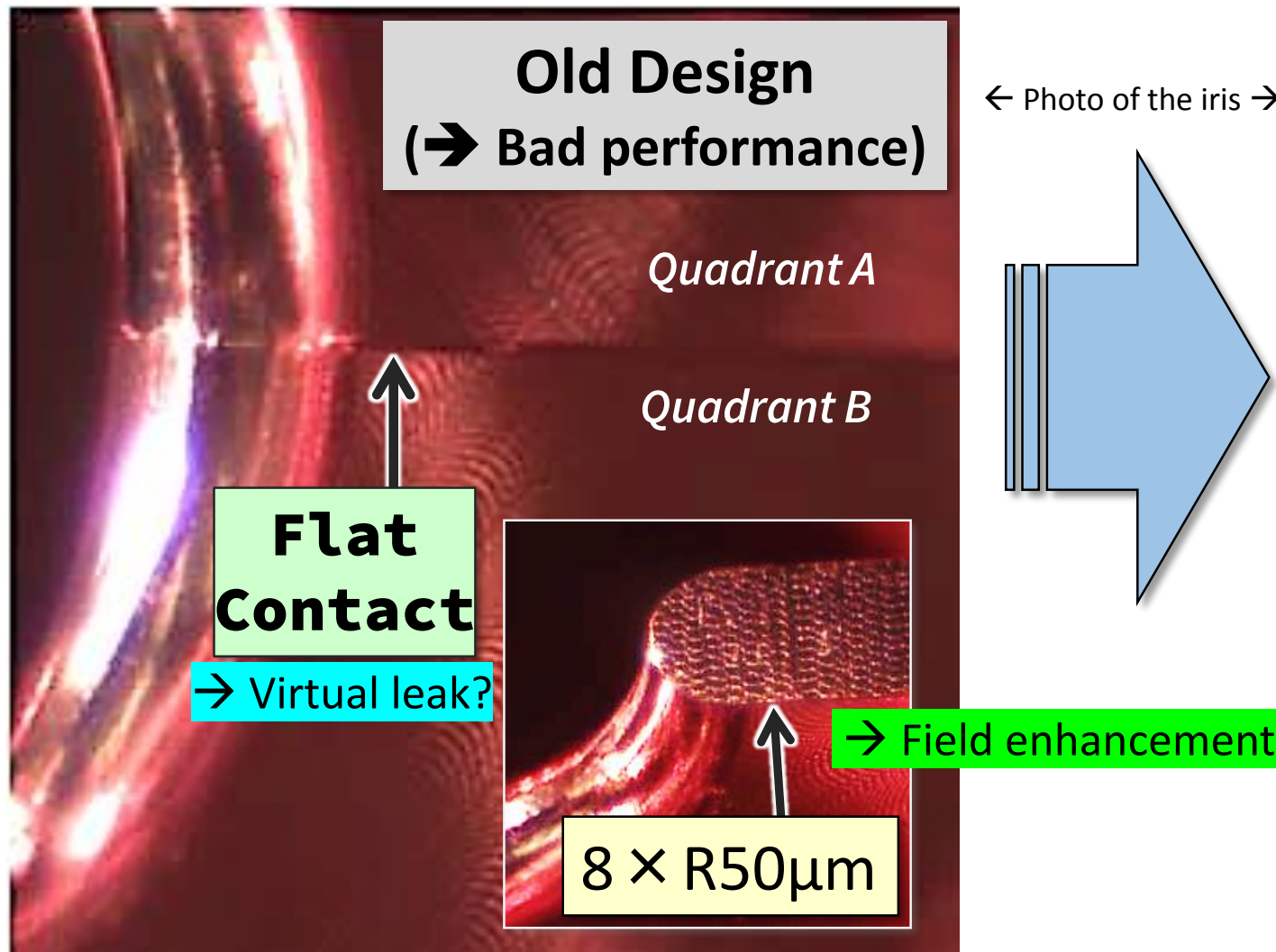
DESIGN IMPROVEMENT

to {
✓ Avoid virtual leak
✓ Suppress the field enhancement

The chamfer radius and small-gap size were optimized based on simulation to minimize

- A) Field enhancement at the corner of the quadrants ($\rightarrow +25\%$)
- B) Deterioration of the shunt impedance ($\rightarrow -2\%$)

For details, see [T. Abe et al., "Fabrication of Quadrant-Type X-Band Single-Cell Structure used for High Gradient Tests," presented at the 11th Annual Meeting of Particle Accelerator Society of Japan \(2014\), Paper ID: SUP042.](#)



Demonstration of the High-Gradient Performance with a single-cell SW cavity

(SW: Standing Wave)

[T. Abe et al., "High-Gradient Test Results on a Quadrant-Type X-Band Single-Cell Structure," presented at the 14th Annual Meeting of Particle Accelerator Society of Japan \(2017\), PaperID: WEP039.](#)

Breakdown-rate meas. after RF conditioning performed at KEK / Nextef / Shield-B
SD1_QUAD-R04G01_K1, 100+150 ns

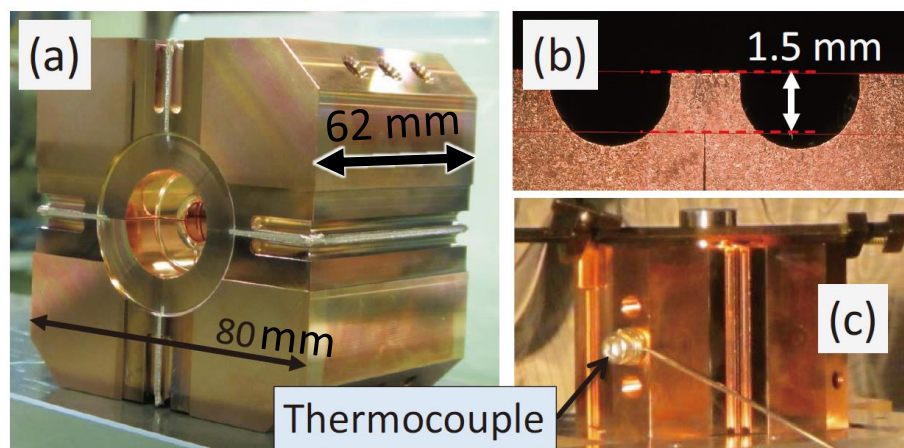
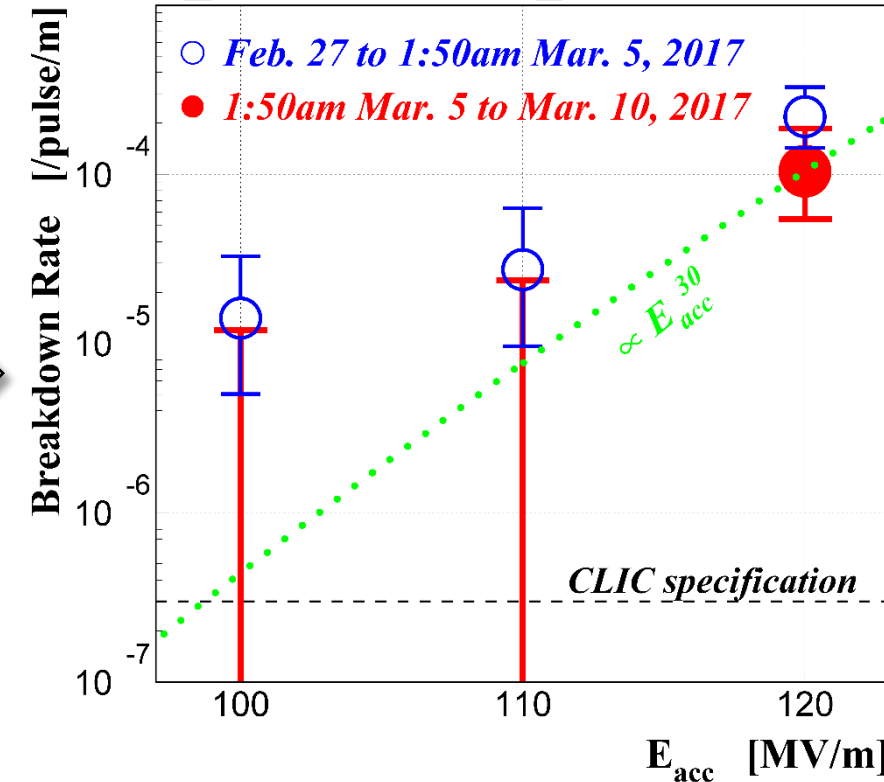
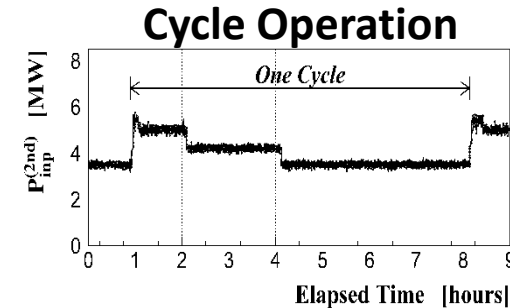


Figure 12: EBW of the quadrants. (a) After the EBW. (b) Welding penetration depth for the EBW conditions described in [13]. (c) A thermocouple is attached.

Good high-gradient performance demonstrated

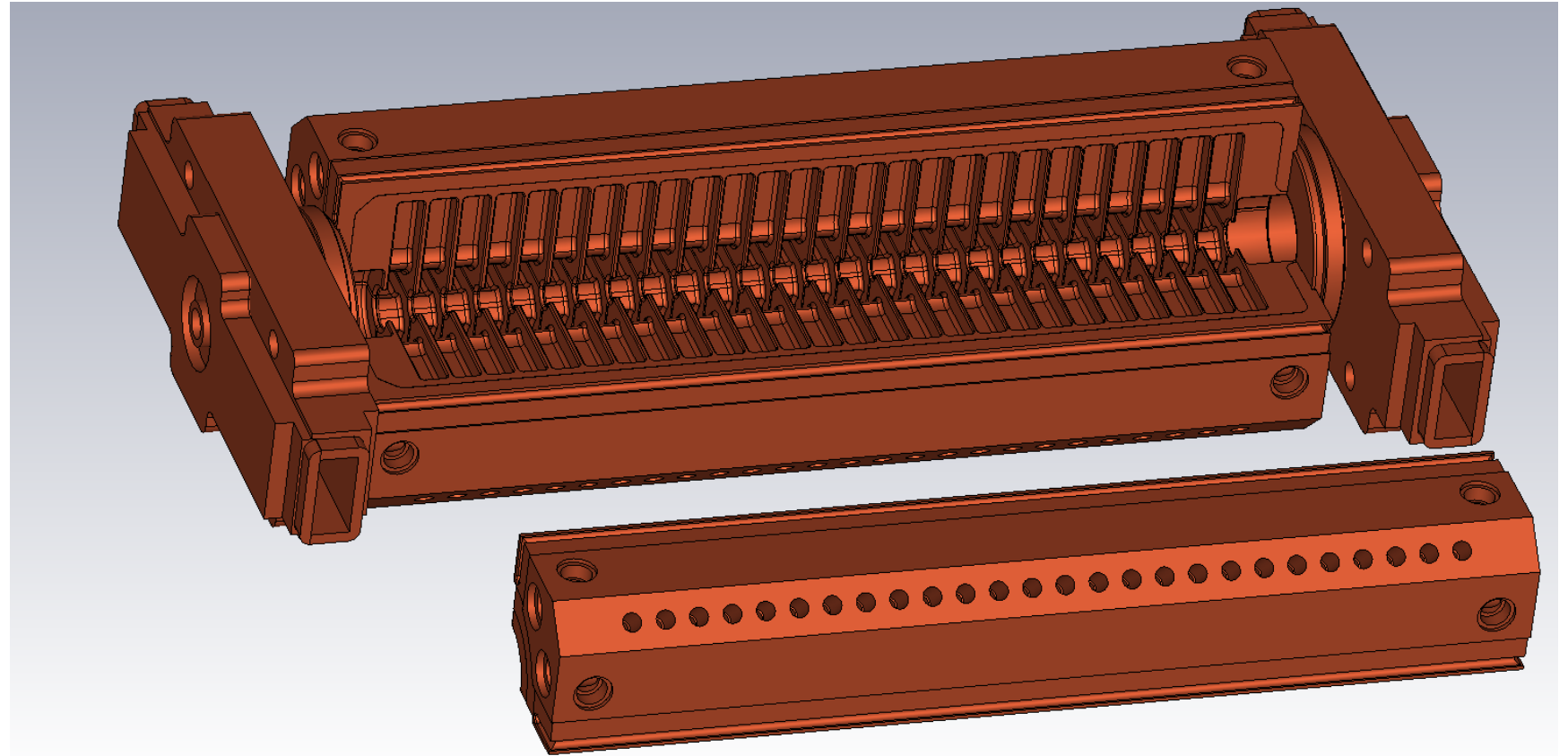
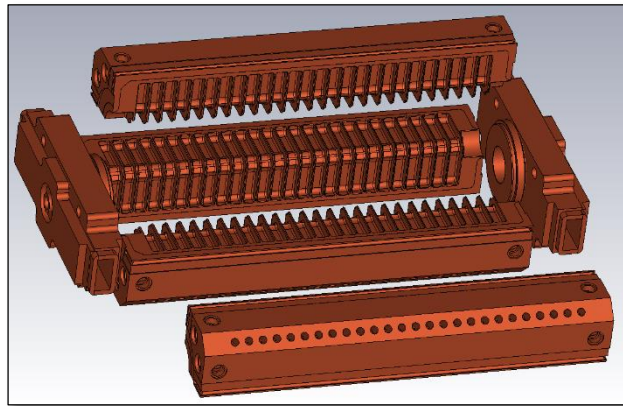
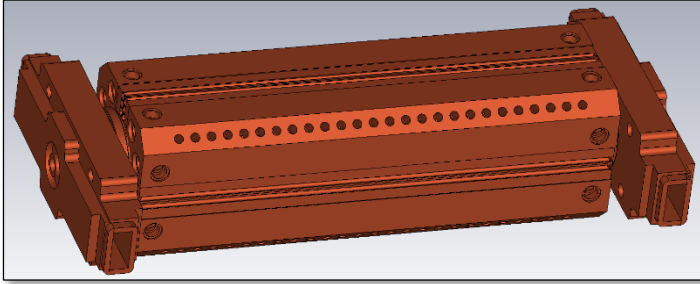
Nest step: Demonstration of the High-Gradient Performance
for a 24-cell TW structure of the CLIC prototype structure:

“TD24R10_QUAD-R04G01”

(TW: Traveling Wave)

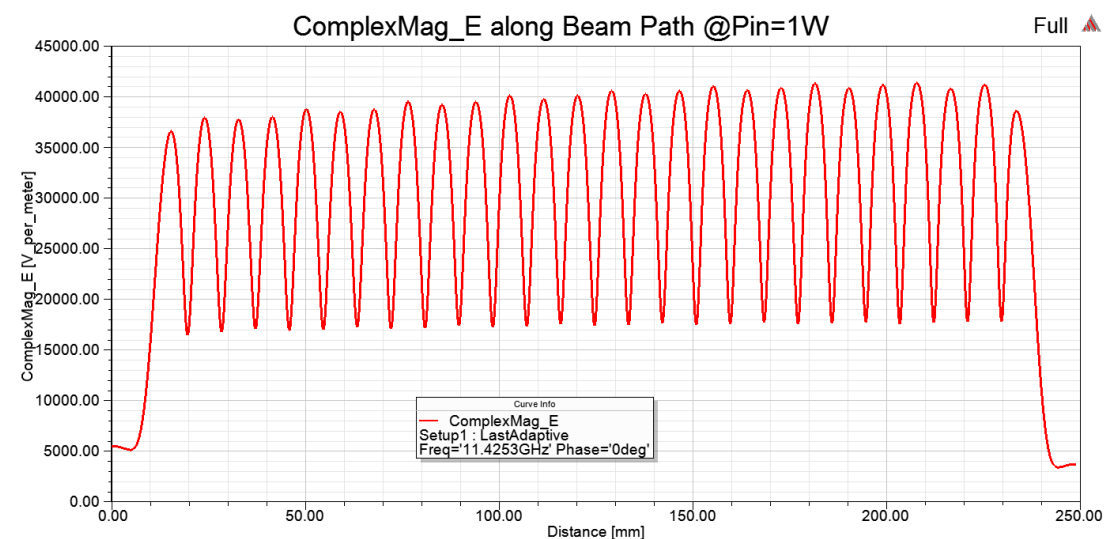
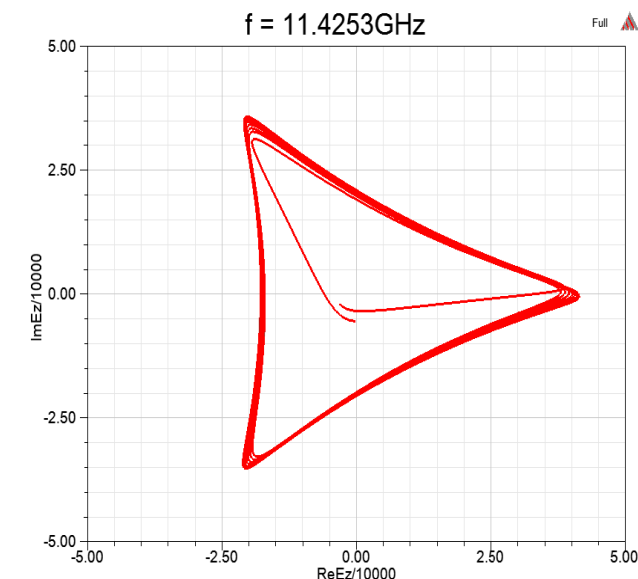
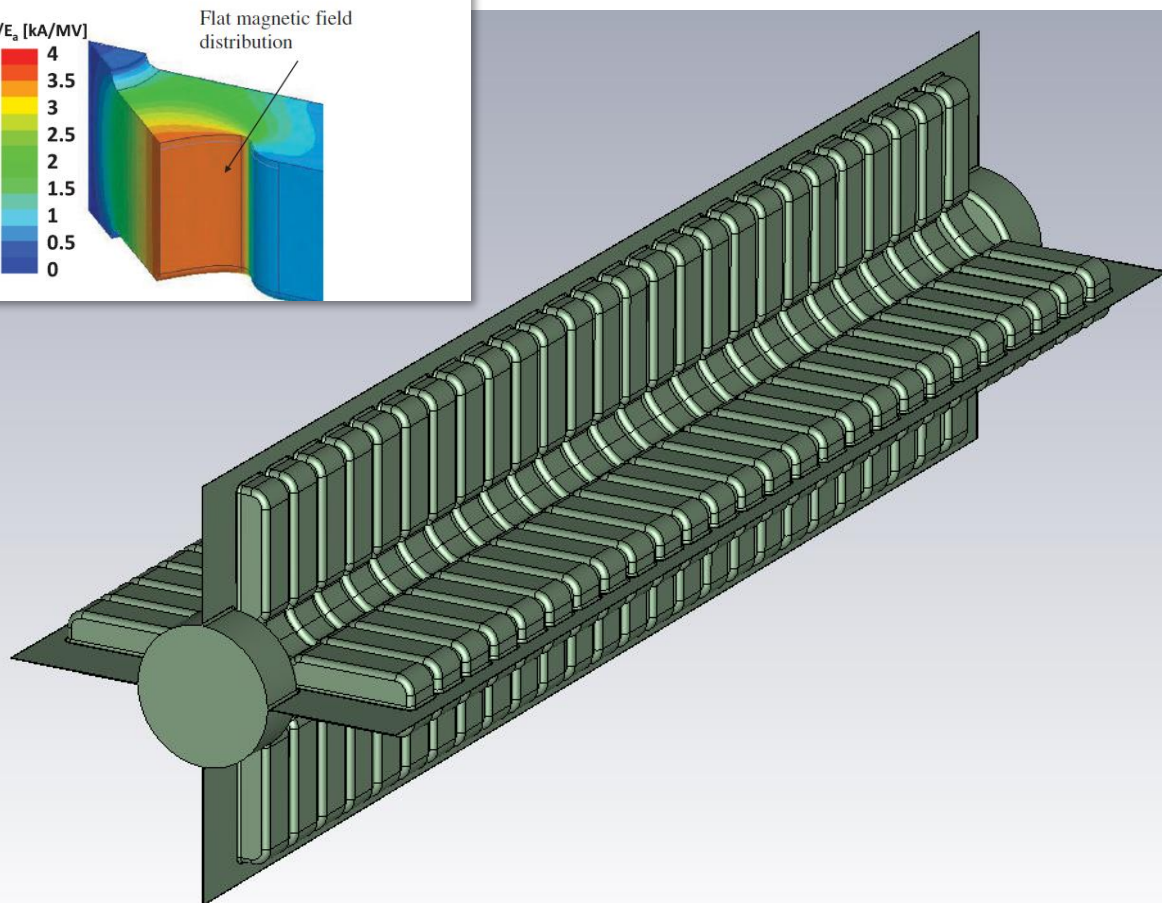
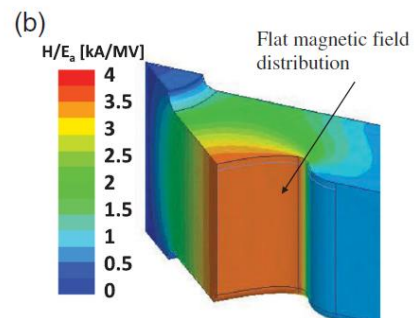
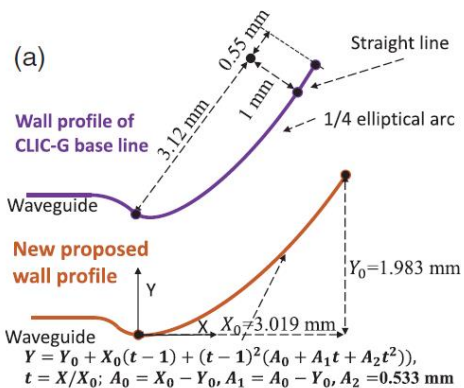
Chamfer radius: 0.4 mm

Gap between quadrants: 0.1 mm

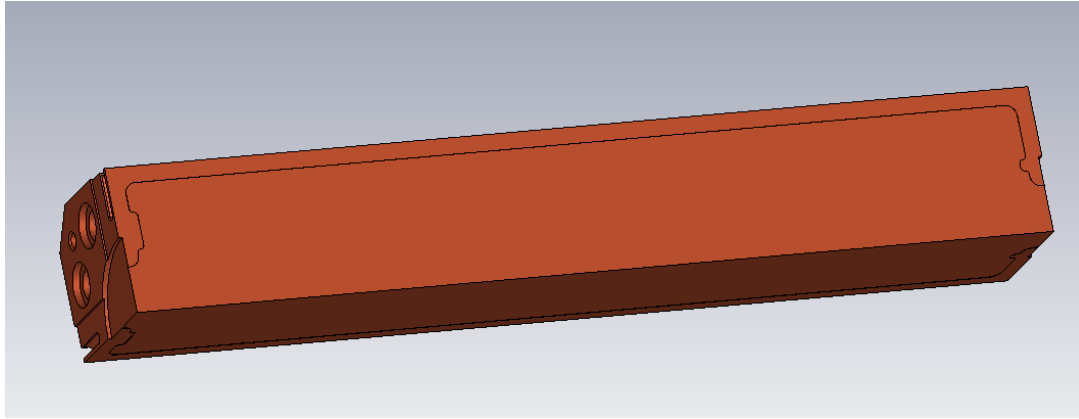


Cavity Design based on CLIC-G*

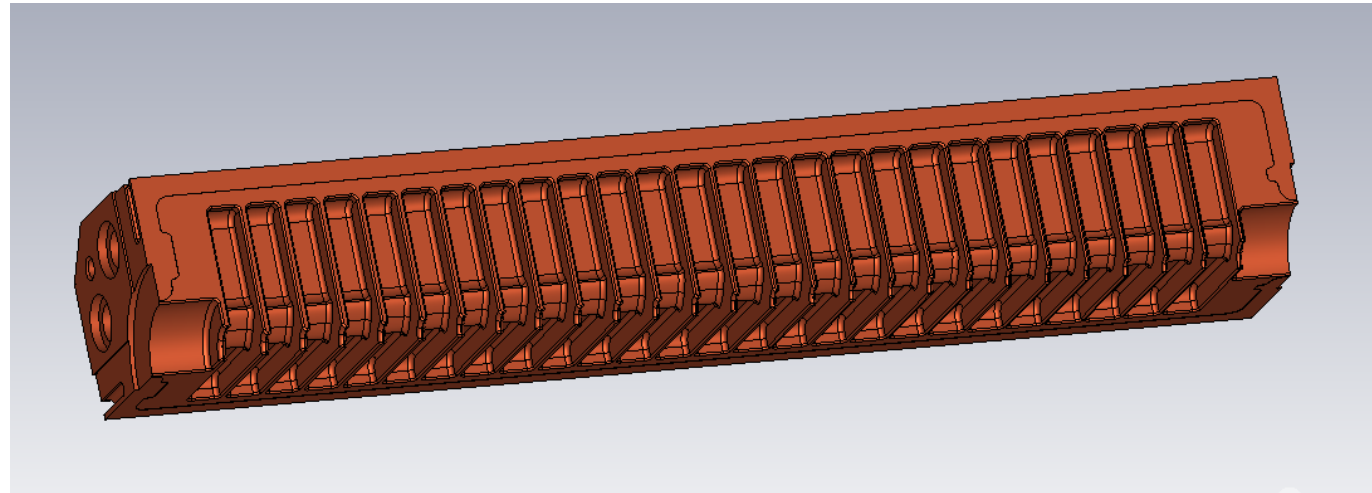
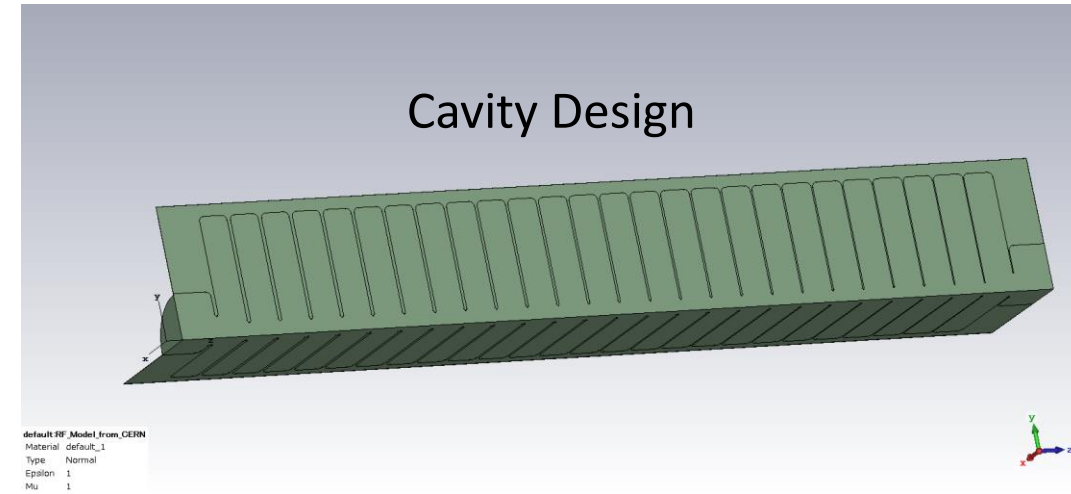
Made by Jiayang Liu (THU) and Alexej Grudiev (CERN)

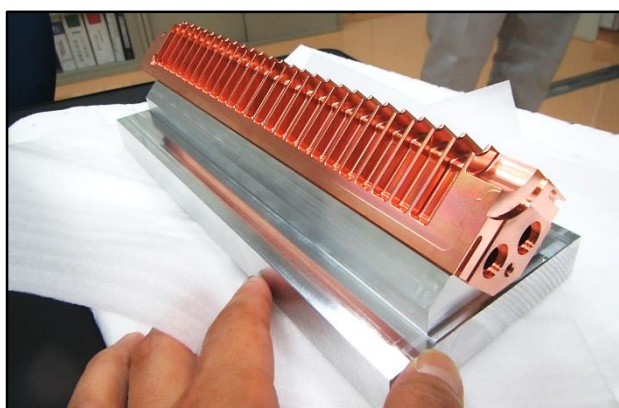


From the Cavity Design to the 3D Mechanical Drawing



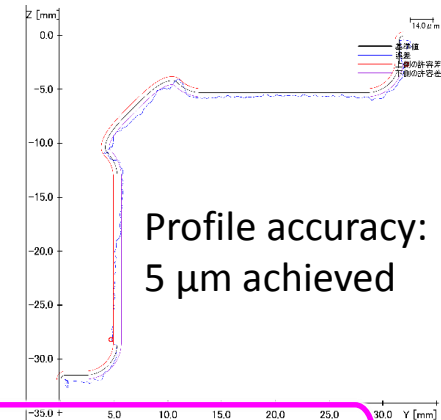
minus



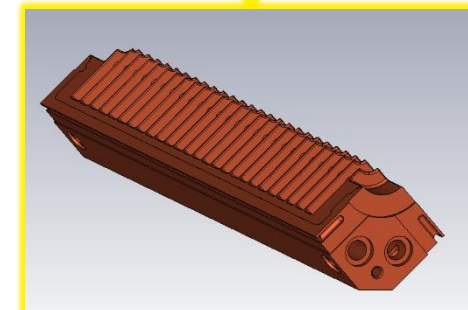
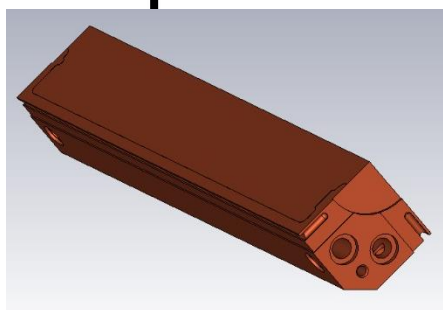
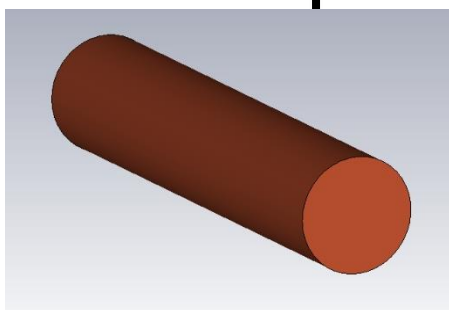


Ultraprecision Milling

- ✓ Machining by U-Corporation
- ✓ Milling machine used: **YASDA H30i** (~1M USD)
- ✓ Tool: carbide ball endmill



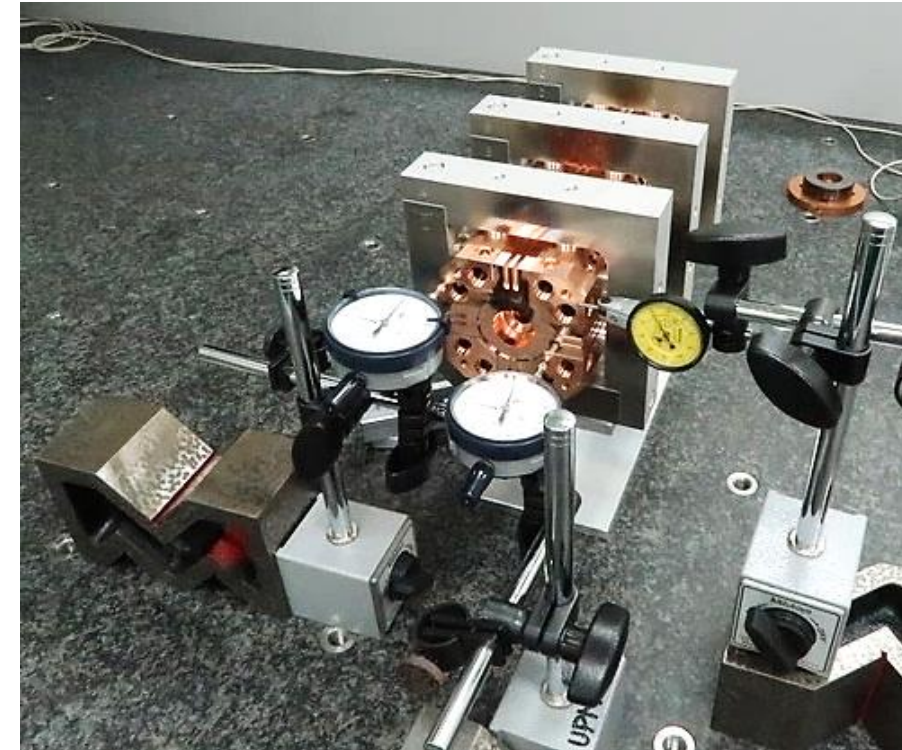
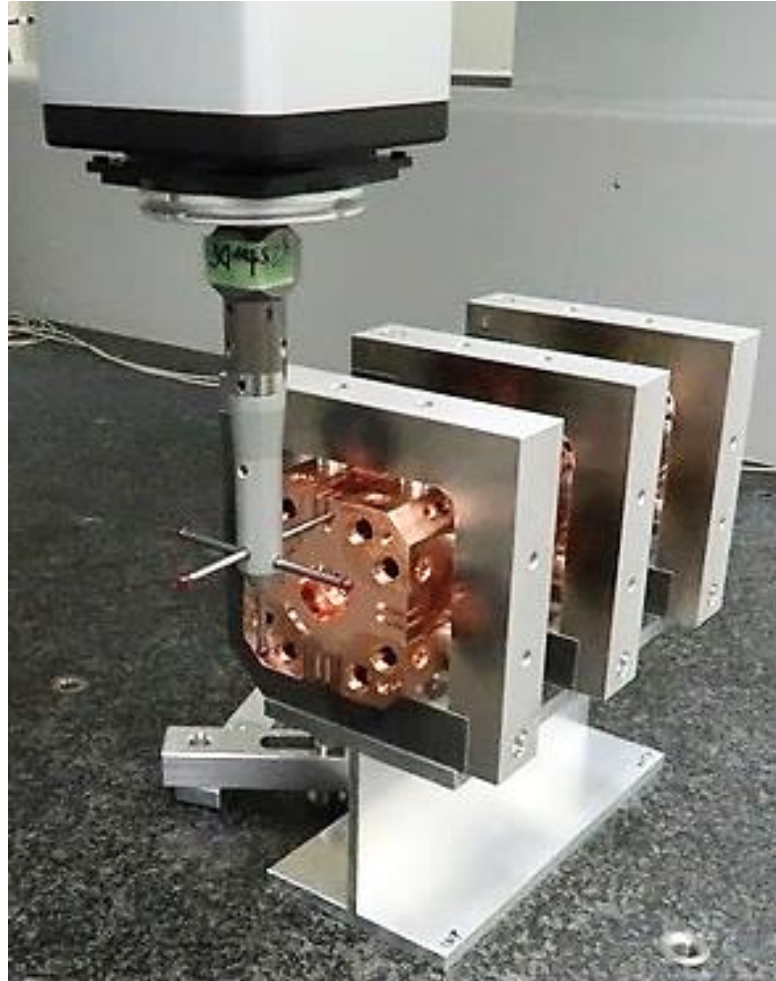
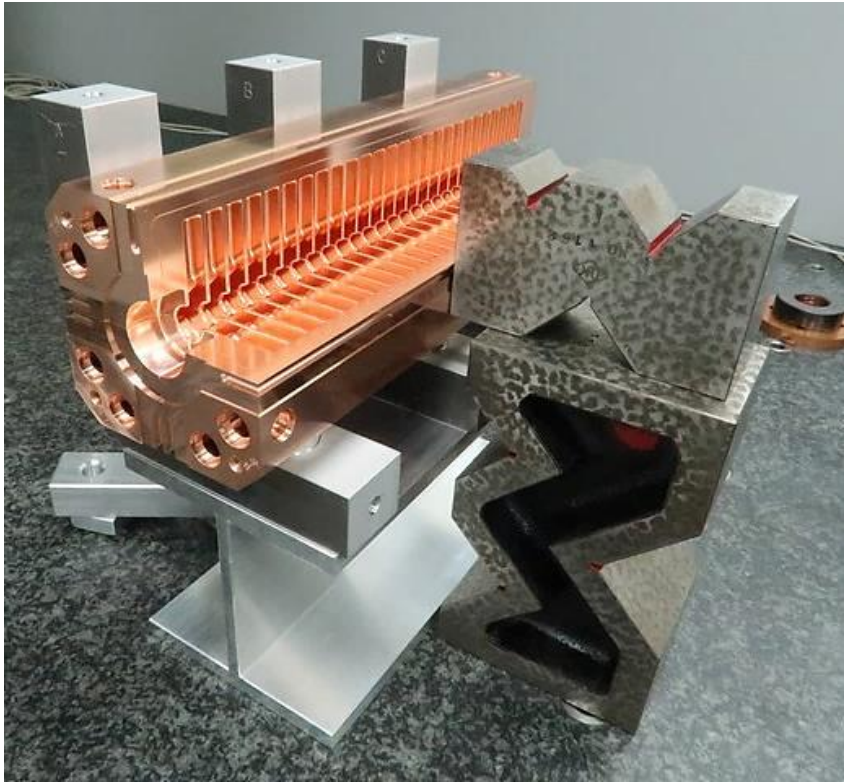
	Step 0	Step 1	Meas.	Step 2	Meas.	Step 3	Meas.	Step 4
Unmachined thickness [mm]		0.1		0.1		0.03		0
Size of the endmill [mm]	Various	R2		R0.75				
Surface roughness achieved	n/a							Ra0.3μm
Machining time / quadrant	13 h	18 h		1 day		2 days		2 days



Machining-time reduction is needed for cost reduction.

Assembly with 5 μm accuracy

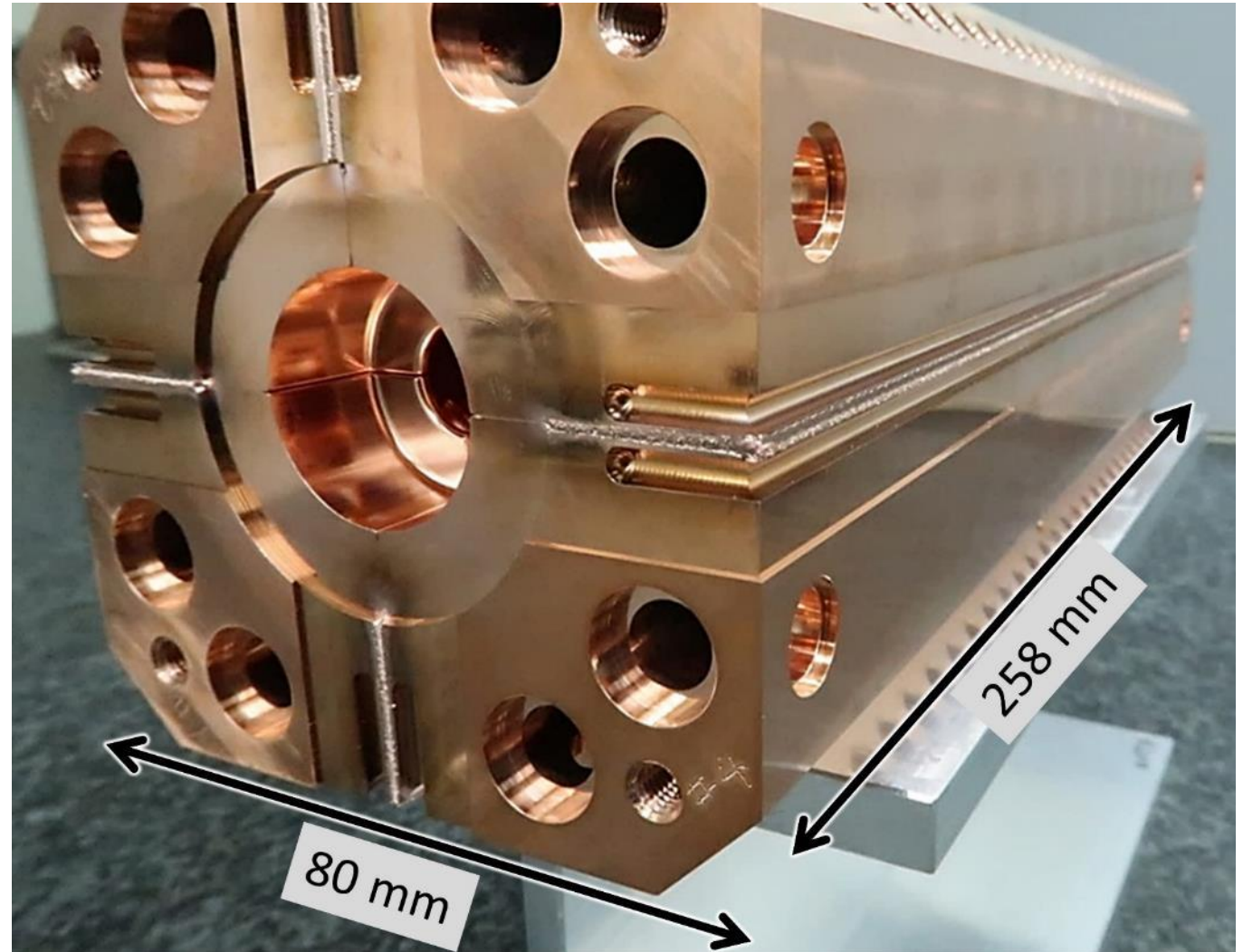
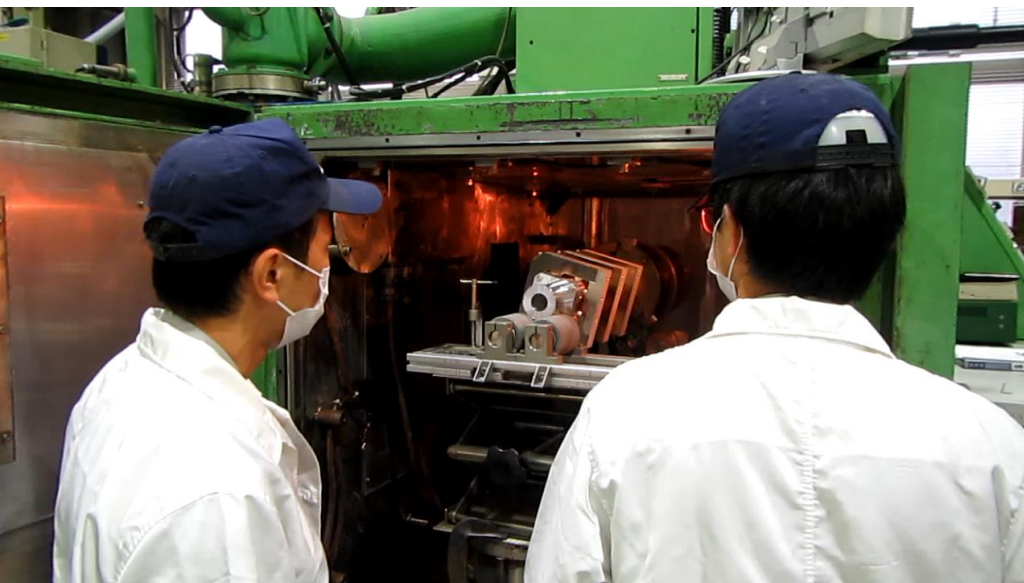
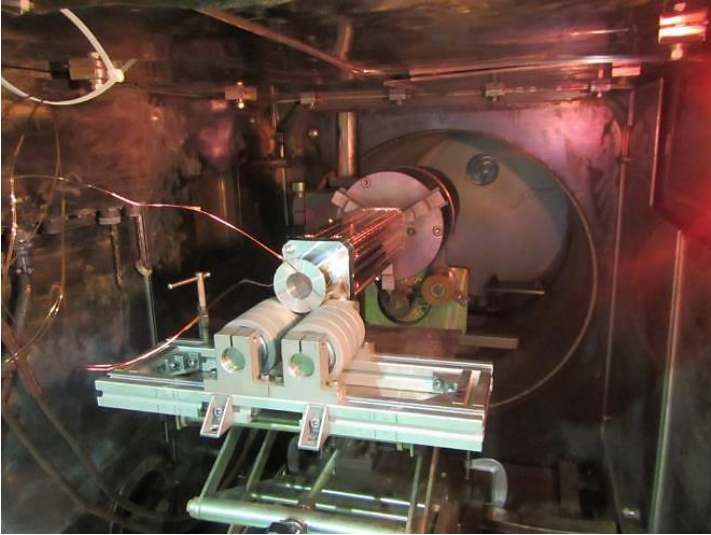
by T. Takatomi



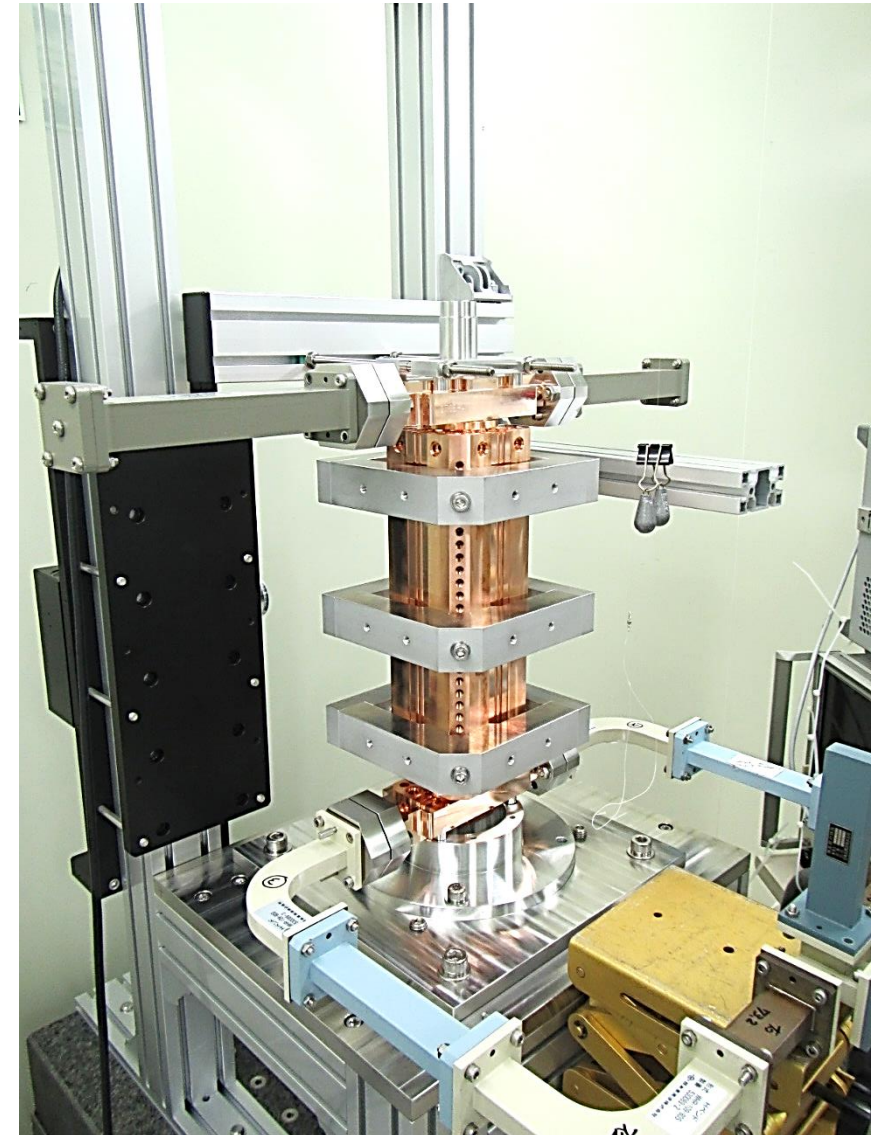
Bonding with Electron Beam Welding (EBW)

by [TAIYO EB tech](#)

After the EBW

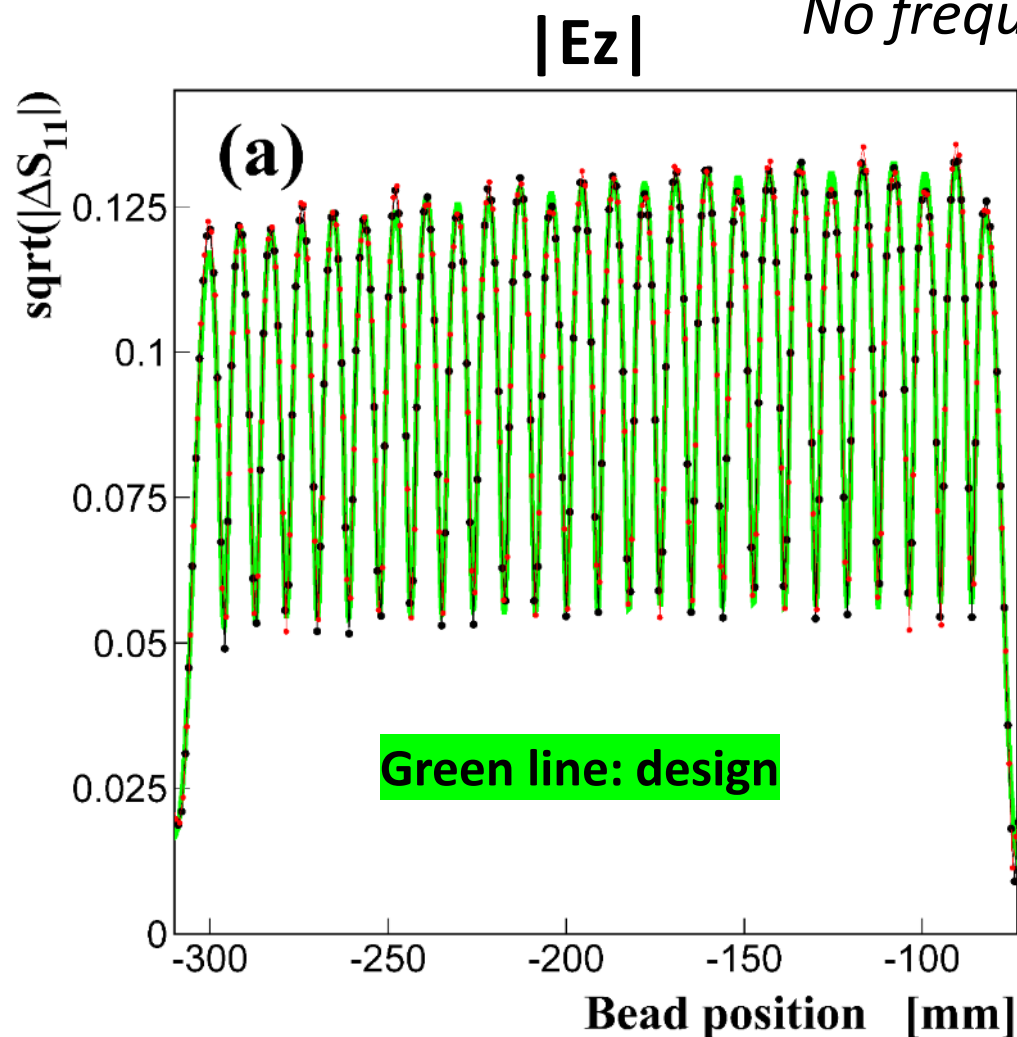


RF Measurement

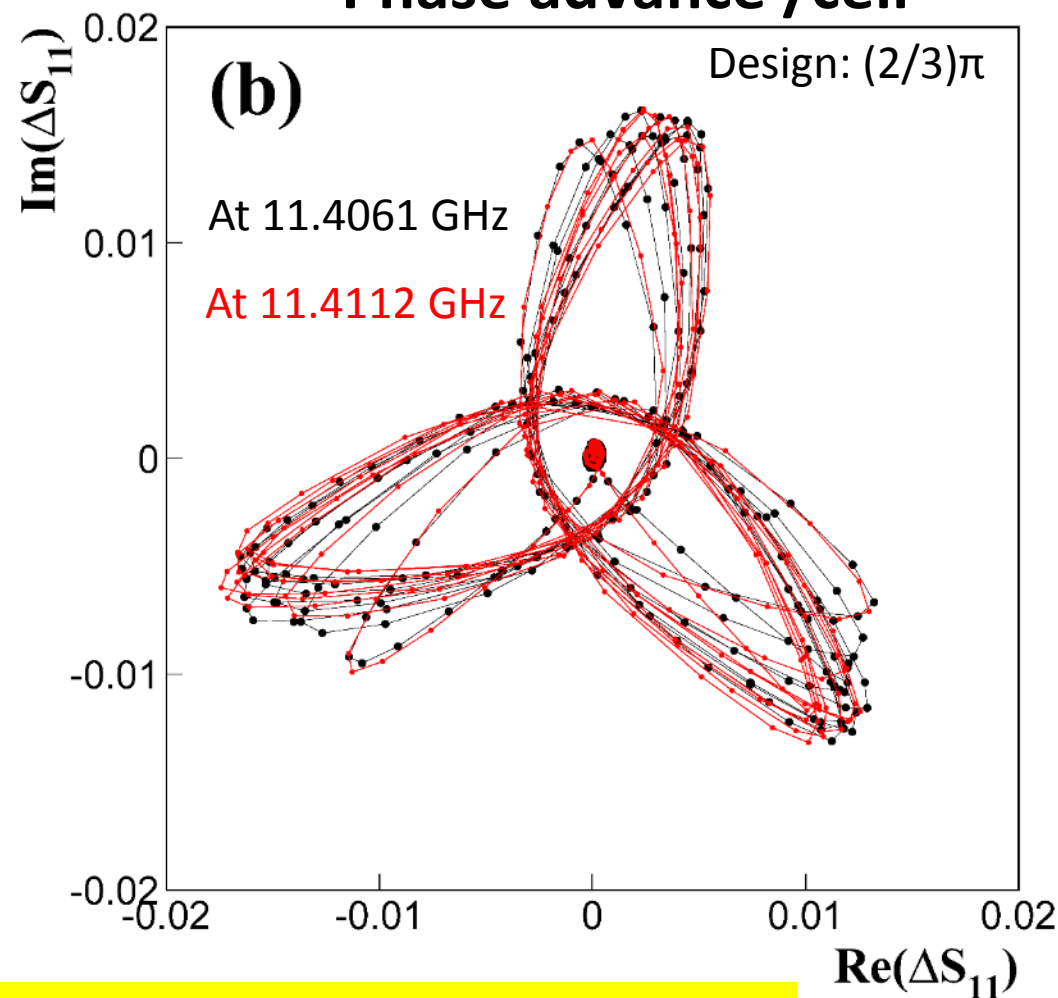


RF Meas. Results before (black) / after (red) the EBW (1/2)

No frequency tuning done yet



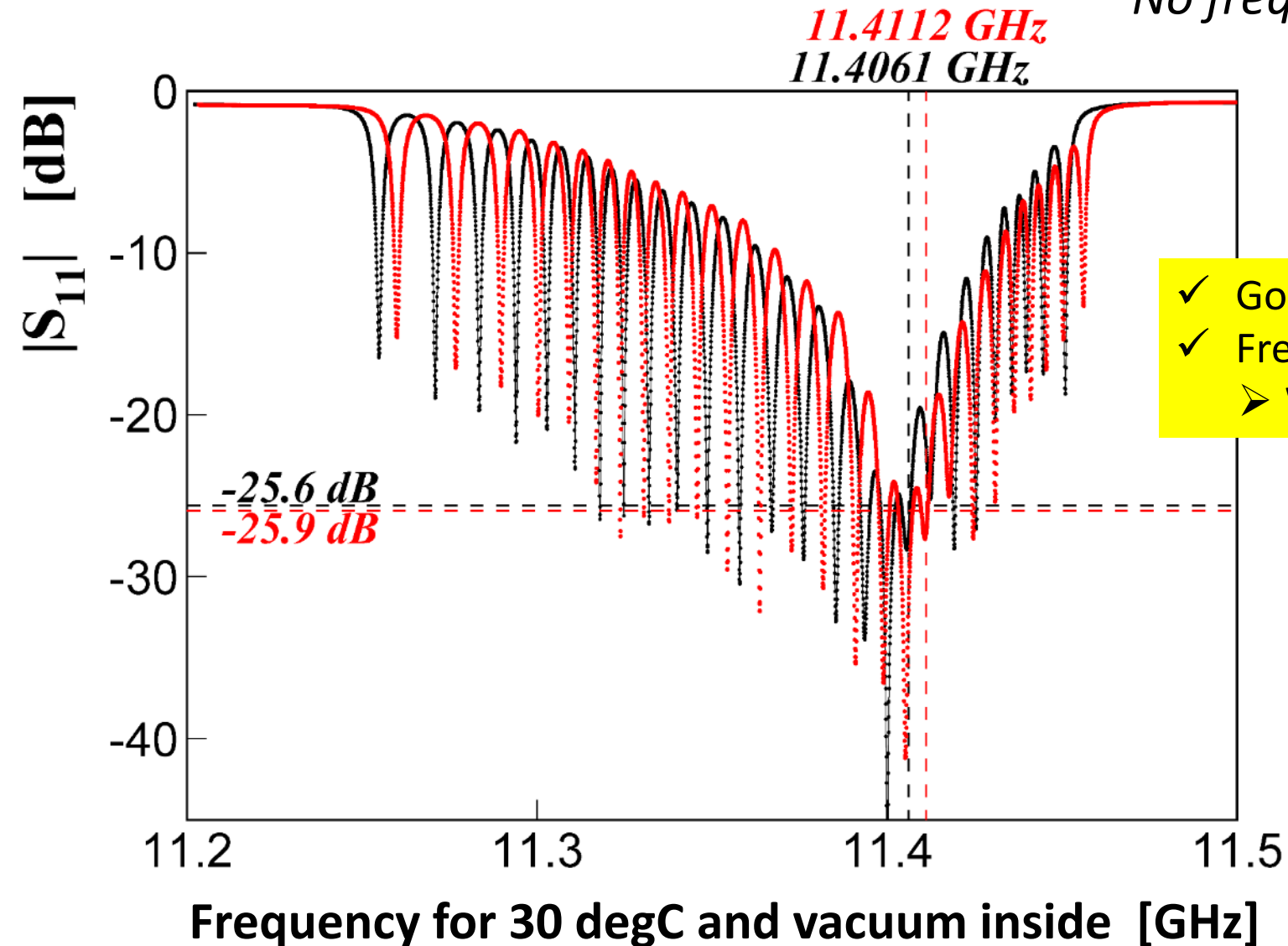
Phase advance /cell



- ✓ No significant difference before and after the EBW
- ✓ These meas. close to the design

RF Meas. Results before (black) / after (red) the EBW (1/2)

No frequency tuning done yet



- ✓ Good matching without tuning ($< -25\text{dB}$)
- ✓ Frequency increased by +5.1 MHz
 - Within tuning range: ± 40 MHz

Transverse-size change by the EBW measured using a CMM

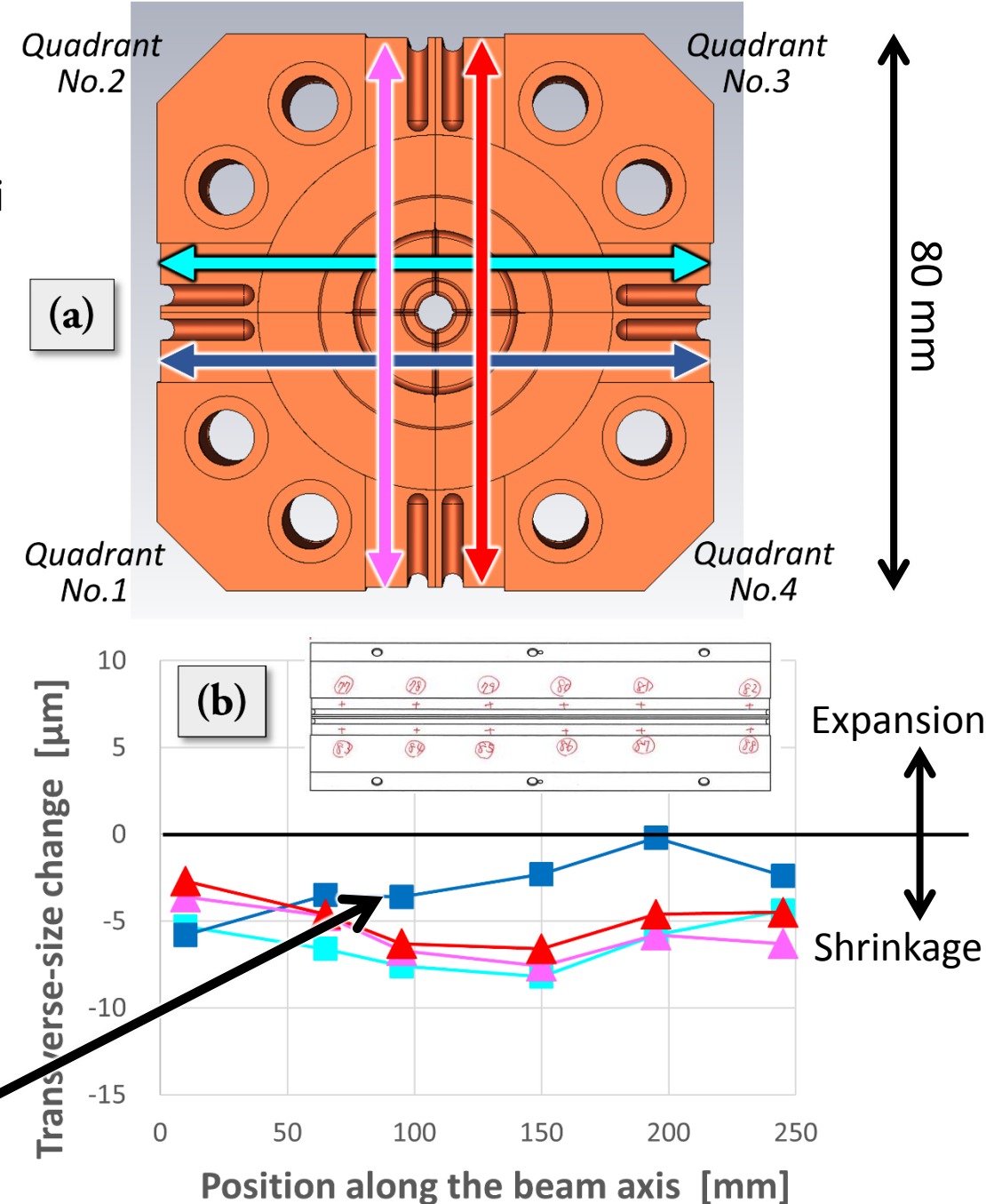
Using Carl Zeiss UPMC 850 CARAT
at KEK / Mechanical Engineering Center

by T. Takatomi



- ✓ 5 μm shrinkage in average
- ✓ Difference among the meas.: 2 to 3 μm

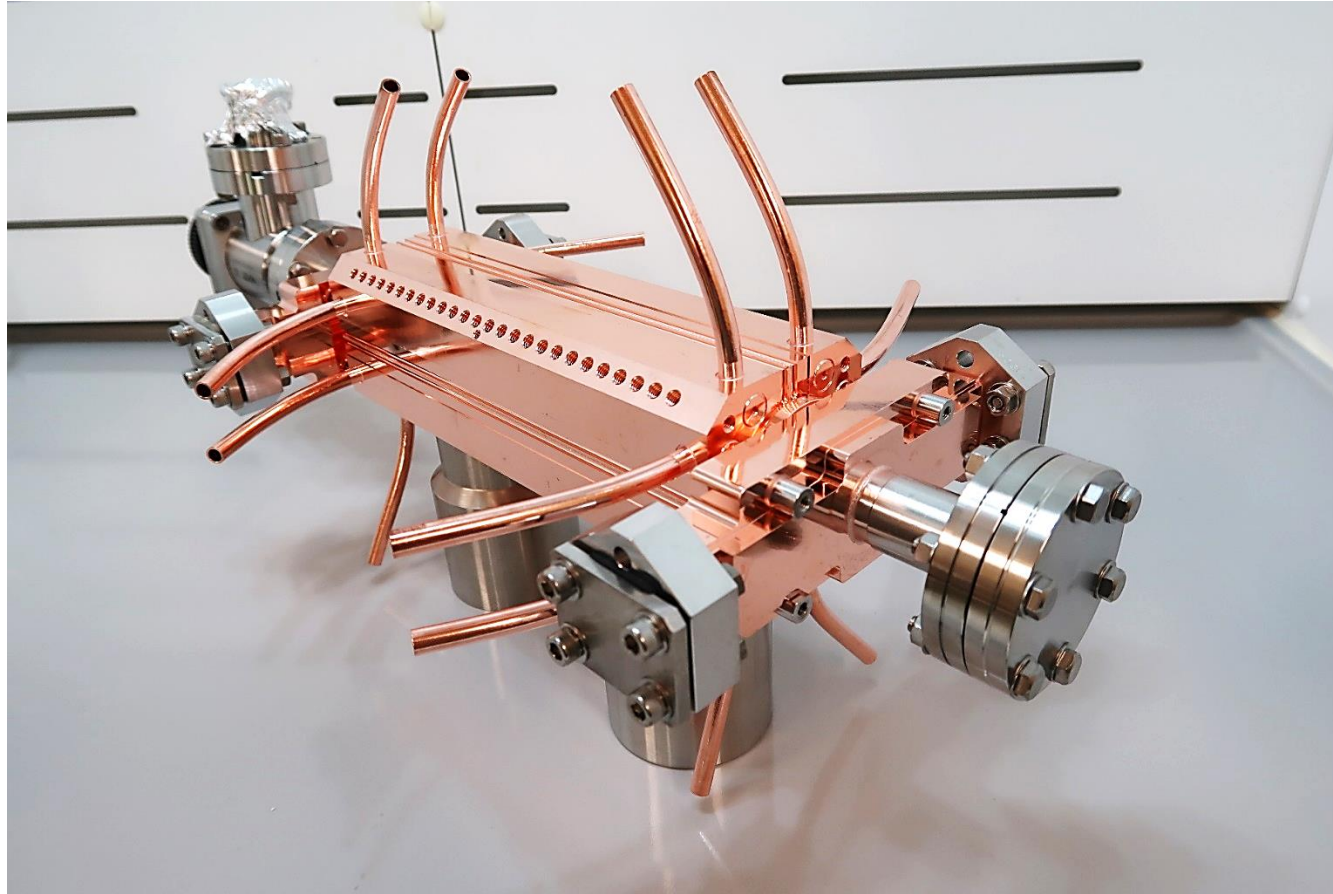
Check of the sequence in the EBW



Summary

- The quadrant(or half)-type fabrication method has advantages that:
 - Surface currents do not flow across any bonding junctions,
 - Possible significant cost reduction in fabrication, and
 - Bonding is easy with EBW without high temperature process.
 - Suitable for fabricating accelerating structures made of harder material with possibly higher high-gradient performance
- The naïve quadrant-type structure showed bad high-gradient performance.
- The design improved, characterized by:
 - Large round chamfer at the edges of quadrants
 - Finite gap between quadrants
- Good high-gradient performance for the improved quadrant-type single-cell SW cavity demonstrated
- The 24-cell TW structure (TD24R10_QUAD) has been fabricated for complete demonstration.
 - The quadrants were bonded with EBW.
 - No significant difference in the RF properties before and after the EBW
 - The frequency change: +5.1 MHz (<< frequency tuning range: ± 40 MHz)
 - The measured RF properties found close to the design without frequency tuning

TD24R10_QUAD-R04G01_K1 fabrication completed



Waiting for high-gradient test...

Thank you for your
attention!